	Hit s	Search Text	DBs
7	36	and ((photoresist or resist or photosensitive) same (pattern or mask) same develop\$4 same (expos\$4 or irradiat\$4 or illuminate or photolithograph\$4))	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB

	Hit s	Search Text	DBs
8	0	same (etch\$4 or RIE)) and ((fill\$4 or deposit\$4 or coat\$4) same (window or opening or (bit\$3line near6 contact near4 window) or (aspect near6 ratio)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB

	Hit s	Search Text	DBs
9	28	same (etch\$4 or RIE)) and ((fill\$4 or deposit\$4 or coat\$4) same (window or opening or (bit\$3line near6 contact near4 window) or (aspect near6 ratio)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB